

NX3L1G3157

Low-ohmic, single-pole, double-throw switch

Rev. 01 — 8 October 2007

Product data sheet

1. General description

The NX3L1G3157 provides one, low-ohmic, single-pole, double-throw analog switch suitable for use as an analog or digital multiplexer/demultiplexer. It has a digital select input (S) with Schmitt-trigger action, two independent inputs/outputs (Y0, Y1) and a common input/output (Z).

Schmitt-trigger action at the select input (S) makes the circuit tolerant to slower input rise and fall times across the entire V_{CC} range from 1.4 V to 3.6 V.

The NX3L1G3157 allows signals with amplitude up to V_{CC} to be transmitted from Z to Y0 or Y1; or from Y0 or Y1 to Z. Its low ON resistance (0.5 Ω) and flatness (0.13 Ω) ensures minimal attenuation and distortion of transmitted signals.

2. Features

- Wide supply voltage range from 1.4 V to 3.6 V
- Very low ON resistance:
 - ◆ 1.6 Ω (typical) at $V_{CC} = 1.4$ V
 - ◆ 1.0 Ω (typical) at $V_{CC} = 1.65$ V
 - ◆ 0.55 Ω (typical) at $V_{CC} = 2.3$ V
 - ◆ 0.50 Ω (typical) at $V_{CC} = 2.7$ V
- Break-before-make switching
- High noise immunity
- ESD protection:
 - ◆ HBM JESD22-A114E Class 3A exceeds 7500 V
 - ◆ MM JESD22-A115-A exceeds 200 V
 - ◆ CDM AEC-Q100-011 revision B exceeds 1000 V
- CMOS low-power consumption
- Latch-up performance exceeds 100 mA per JESD 78 Class II Level B
- Direct interface with TTL levels at 3.0 V
- Control input accepts voltages above supply voltage
- High current handling capability (350 mA continuous current under 3.3 V supply)
- Specified from -40 °C to $+85$ °C and from -40 °C to $+125$ °C

3. Applications

- Cell phone
- PDA
- Portable media player

4. Ordering information

Table 1. Ordering information

Type number	Package			Version
	Temperature range	Name	Description	
NX3L1G3157GM	-40 °C to +125 °C	XSON6	plastic extremely thin small outline package; no leads; 6 terminals; body 1 × 1.45 × 0.5 mm	SOT886

5. Marking

Table 2. Marking

Type number	Marking code
NX3L1G3157GM	MJ

6. Functional diagram

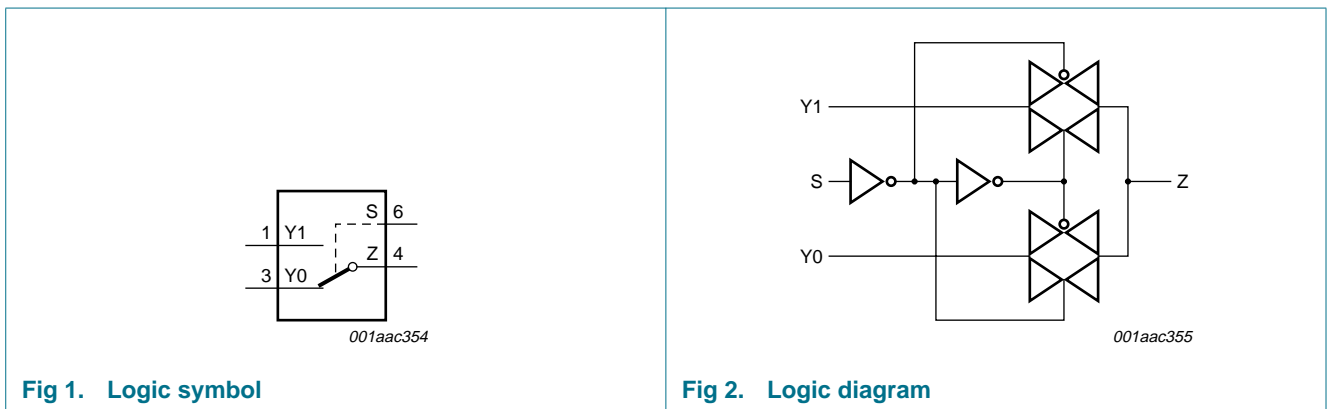


Fig 1. Logic symbol

Fig 2. Logic diagram

7. Pinning information

7.1 Pinning

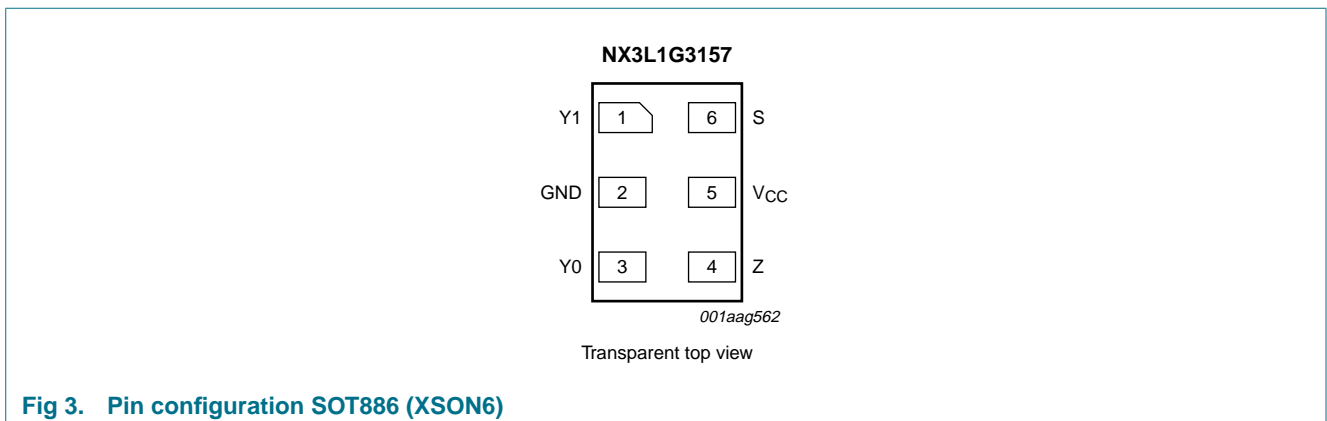


Fig 3. Pin configuration SOT886 (XSON6)

7.2 Pin description

Table 3. Pin description

Symbol	Pin	Description
Y1	1	independent input or output
GND	2	ground (0 V)
Y0	3	independent input or output
Z	4	common output or input
V _{CC}	5	supply voltage
S	6	select input

8. Functional description

Table 4. Function table^[1]

Input S	Channel on
L	Y0
H	Y1

- [1] H = HIGH voltage level;
L = LOW voltage level.

9. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134). Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	Min	Max	Unit
V _{CC}	supply voltage		-0.5	+4.6	V
V _I	input voltage		^[1] -0.5	+4.6	V
V _{SW}	switch voltage		^[2] -0.5	V _{CC} + 0.5	V
I _{IK}	input clamping current	V _I < -0.5 V	-50	-	mA
I _{SK}	switch clamping current	V _I < -0.5 V or V _I > V _{CC} + 0.5 V	-	±50	mA
I _{SW}	switch current	V _{SW} > -0.5 V or V _{SW} < V _{CC} + 0.5 V; source or sink current	-	±350	mA
		V _{SW} > -0.5 V or V _{SW} < V _{CC} + 0.5 V; pulsed at 1 ms duration, < 10 % duty cycle; peak current	-	±500	mA
T _{stg}	storage temperature		-65	+150	°C
P _{tot}	total power dissipation	T _{amb} = -40 °C to +125 °C	^[3] -	250	mW

- [1] The minimum input voltage rating may be exceeded if the input current rating is observed.
 [2] The minimum and maximum switch voltage ratings may be exceeded if the switch clamping current rating is observed.
 [3] For XSON6 packages: above 45 °C the value of P_{tot} derates linearly with 2.4 mW/K.

10. Recommended operating conditions

Table 6. Recommended operating conditions

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
V _{CC}	supply voltage		1.4	-	3.6	V
V _I	input voltage	select input S	0	-	3.6	V
V _{SW}	switch voltage		[1] 0	-	V _{CC}	V
T _{amb}	ambient temperature		-40	-	+125	°C
Δt/ΔV	input transition rise and fall rate	V _{CC} = 1.4 V to 3.6 V	[2] -	-	200	ns/V

[1] To avoid sinking GND current from terminal Z when switch current flows in terminal Yn, the voltage drop across the bidirectional switch must not exceed 0.4 V. If the switch current flows into terminal Z, no GND current will flow from terminal Yn. In this case, there is no limit for the voltage drop across the switch.

[2] Applies to control signal levels.

11. Static characteristics

Table 7. Static characteristics

At recommended operating conditions; voltages are referenced to GND (ground 0 V).

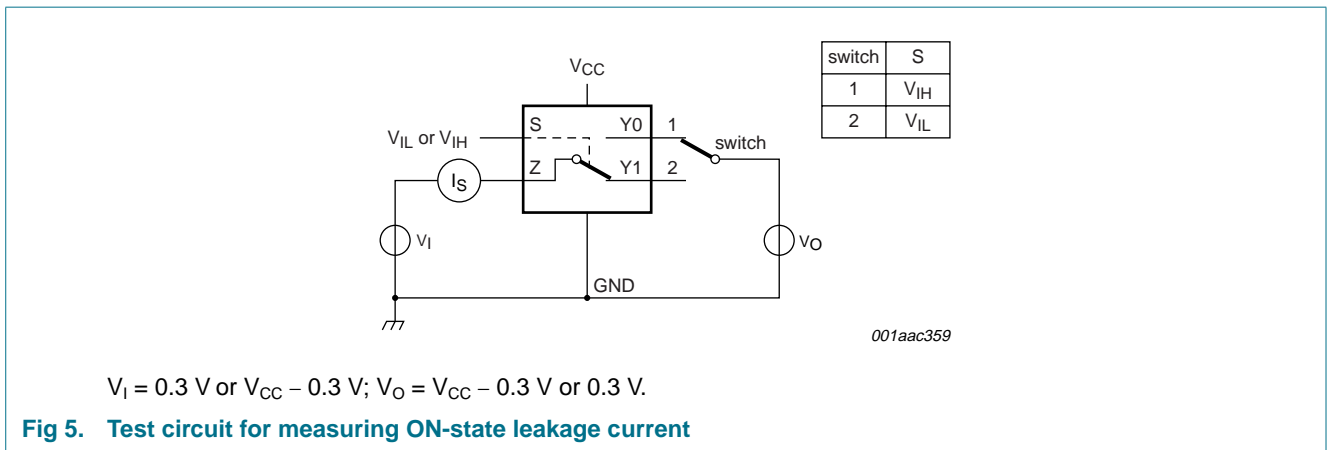
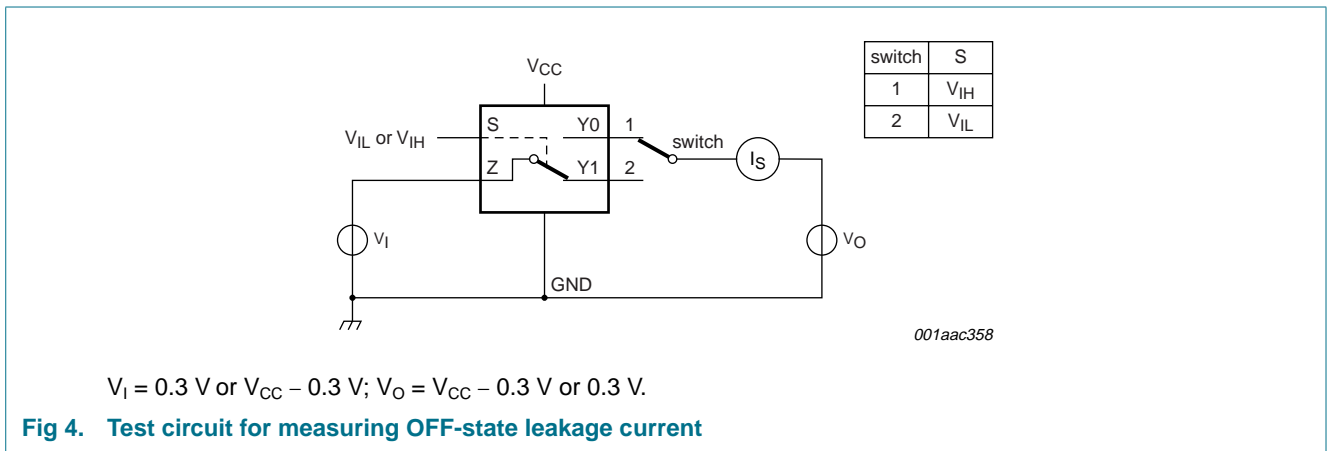
Symbol	Parameter	Conditions	25 °C			-40 °C to +125 °C			Unit
			Min	Typ	Max	Min	Max (85 °C)	Max (125 °C)	
V _{IH}	HIGH-level input voltage	V _{CC} = 1.4 V to 1.95 V	0.65V _{CC}	-	-	0.65V _{CC}	-	-	V
		V _{CC} = 2.3 V to 2.7 V	1.7	-	-	1.7	-	-	V
		V _{CC} = 2.7 V to 3.6 V	2.0	-	-	2.0	-	-	V
V _{IL}	LOW-level input voltage	V _{CC} = 1.4 V to 1.95 V	-	-	0.35V _{CC}	-	0.35V _{CC}	0.35V _{CC}	V
		V _{CC} = 2.3 V to 2.7 V	-	-	0.7	-	0.7	0.7	V
		V _{CC} = 2.7 V to 3.6 V	-	-	0.8	-	0.8	0.8	V
I _I	input leakage current	select input S; V _I = GND to 3.6 V; V _{CC} = 1.4 V to 3.6 V	-	-	-	-	±0.5	±1	μA
I _{S(OFF)}	OFF-state leakage current	Y0 and Y1 port; V _{CC} = 1.4 V to 3.6 V; see Figure 4	-	-	±5	-	±50	±500	nA
I _{S(ON)}	ON-state leakage current	Z port; V _{CC} = 1.4 V to 3.6 V; see Figure 5	-	-	±5	-	±50	±500	nA
I _{CC}	supply current	V _I = V _{CC} or GND; V _{CC} = 3.6 V; V _{SW} = GND or V _{CC}	-	-	100	-	690	6000	nA
C _I	input capacitance		-	1.0	-	-	-	-	pF

Table 7. Static characteristics ...continued

At recommended operating conditions; voltages are referenced to GND (ground 0 V).

Symbol	Parameter	Conditions	25 °C			-40 °C to +125 °C			Unit
			Min	Typ	Max	Min	Max (85 °C)	Max (125 °C)	
$C_{S(OFF)}$	OFF-state capacitance		-	35	-	-	-	-	pF
$C_{S(ON)}$	ON-state capacitance		-	130	-	-	-	-	pF

11.1 Test circuits



11.2 ON resistance

Table 8. ON resistance

At recommended operating conditions; voltages are referenced to GND (ground = 0 V); for graphs see [Figure 7](#) to [Figure 12](#).

Symbol	Parameter	Conditions	-40 °C to +85 °C			-40 °C to +125 °C		Unit	
			Min	Typ ^[1]	Max	Min	Max		
R _{ON(peak)}	ON resistance (peak)	V _I = GND to V _{CC} ; I _{SW} = 100 mA; see Figure 6							
			V _{CC} = 1.4 V	-	1.6	4.5	-	5.5	Ω
			V _{CC} = 1.65 V	-	1.0	2.0	-	2.5	Ω
			V _{CC} = 2.3 V	-	0.55	0.8	-	1.0	Ω
		V _{CC} = 2.7 V	-	0.5	0.75	-	0.9	Ω	
ΔR _{ON}	ON resistance mismatch between channels	V _I = GND to V _{CC} ; I _{SW} = 100 mA							
			V _{CC} = 1.4 V	-	0.08	0.3	-	0.3	Ω
			V _{CC} = 1.65 V	-	0.08	0.2	-	0.3	Ω
			V _{CC} = 2.3 V	-	0.07	0.2	-	0.2	Ω
		V _{CC} = 2.7 V	-	0.07	0.2	-	0.2	Ω	
R _{ON(flat)}	ON resistance (flatness)	V _I = GND to V _{CC} ; I _{SW} = 100 mA							
			V _{CC} = 1.4 V	-	1.0	4.0	-	4.0	Ω
			V _{CC} = 1.65 V	-	0.5	1.5	-	1.5	Ω
			V _{CC} = 2.3 V	-	0.15	0.3	-	0.35	Ω
		V _{CC} = 2.7 V	-	0.13	0.3	-	0.35	Ω	

[1] Typical values are measured at T_{amb} = 25 °C.

[2] Measured at identical V_{CC}, temperature and input voltage.

[3] Flatness is defined as the difference between the maximum and minimum value of ON resistance measured at identical V_{CC} and temperature.

11.3 ON resistance test circuit and graphs

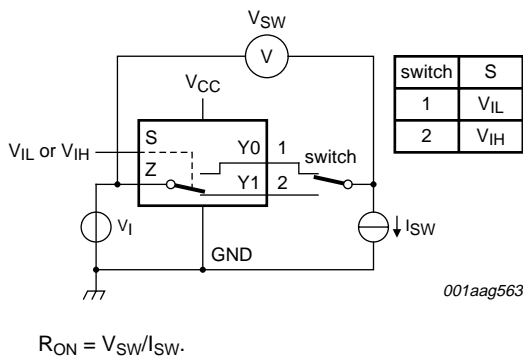
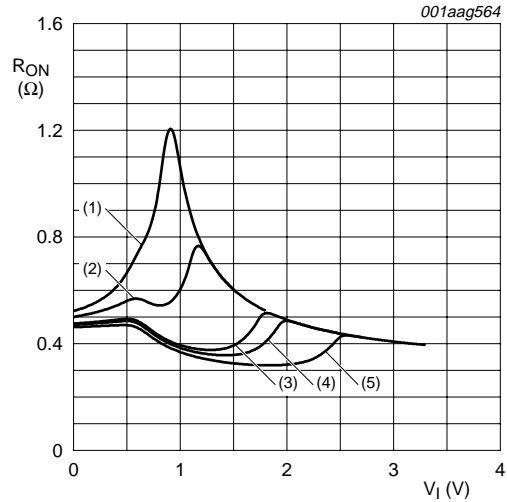
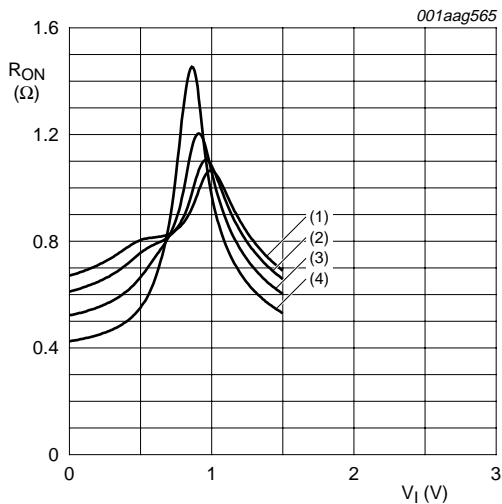


Fig 6. Test circuit for measuring ON resistance



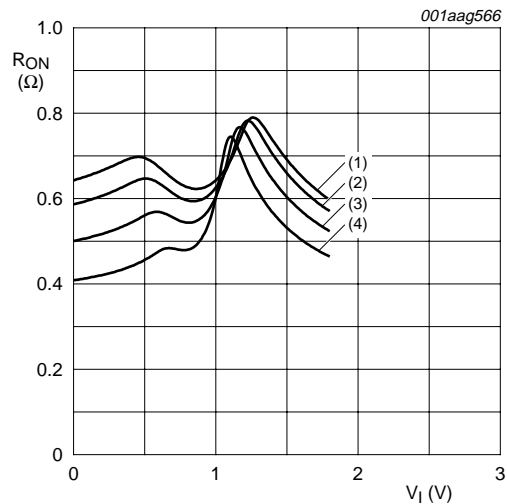
- (1) V_{CC} = 1.5 V.
 - (2) V_{CC} = 1.8 V.
 - (3) V_{CC} = 2.5 V.
 - (4) V_{CC} = 2.7 V.
 - (5) V_{CC} = 3.3 V.
- Measured at T_{amb} = 25 °C.

Fig 7. Typical ON resistance as a function of input voltage



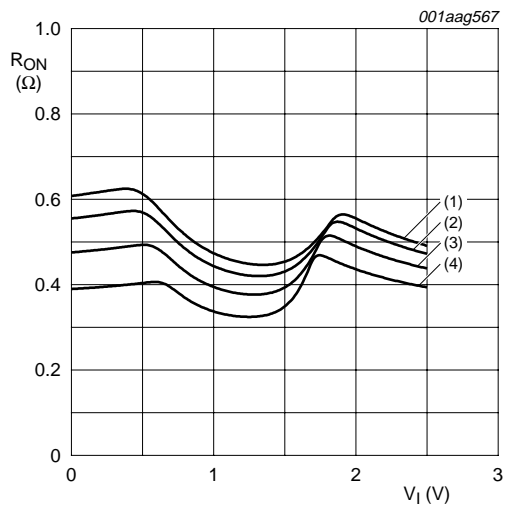
- (1) T_{amb} = 125 °C.
- (2) T_{amb} = 85 °C.
- (3) T_{amb} = 25 °C.
- (4) T_{amb} = -40 °C.

Fig 8. ON resistance as a function of input voltage; V_{CC} = 1.5 V



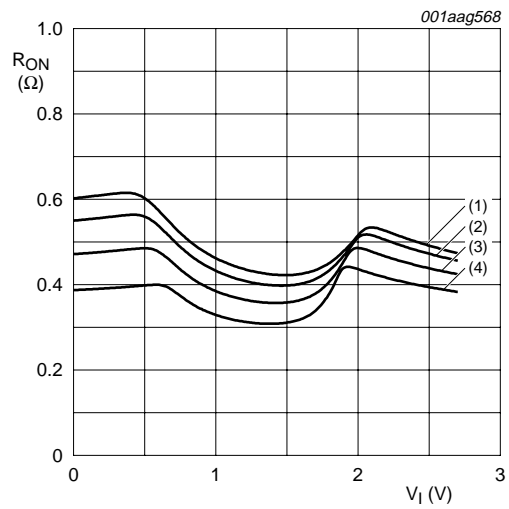
- (1) T_{amb} = 125 °C.
- (2) T_{amb} = 85 °C.
- (3) T_{amb} = 25 °C.
- (4) T_{amb} = -40 °C.

Fig 9. ON resistance as a function of input voltage; V_{CC} = 1.8 V



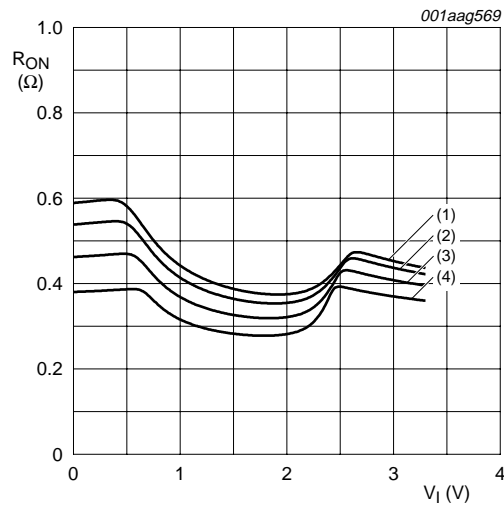
- (1) $T_{amb} = 125\text{ }^{\circ}\text{C}$.
- (2) $T_{amb} = 85\text{ }^{\circ}\text{C}$.
- (3) $T_{amb} = 25\text{ }^{\circ}\text{C}$.
- (4) $T_{amb} = -40\text{ }^{\circ}\text{C}$.

Fig 10. ON resistance as a function of input voltage; $V_{CC} = 2.5\text{ V}$



- (1) $T_{amb} = 125\text{ }^{\circ}\text{C}$.
- (2) $T_{amb} = 85\text{ }^{\circ}\text{C}$.
- (3) $T_{amb} = 25\text{ }^{\circ}\text{C}$.
- (4) $T_{amb} = -40\text{ }^{\circ}\text{C}$.

Fig 11. ON resistance as a function of input voltage; $V_{CC} = 2.7\text{ V}$



- (1) $T_{amb} = 125\text{ }^{\circ}\text{C}$.
- (2) $T_{amb} = 85\text{ }^{\circ}\text{C}$.
- (3) $T_{amb} = 25\text{ }^{\circ}\text{C}$.
- (4) $T_{amb} = -40\text{ }^{\circ}\text{C}$.

Fig 12. ON resistance as a function of input voltage; $V_{CC} = 3.3\text{ V}$

12. Dynamic characteristics

Table 9. Dynamic characteristics

At recommended operating conditions; voltages are referenced to GND (ground = 0 V); for load circuit see [Figure 15](#).

Symbol	Parameter	Conditions	25 °C			-40 °C to +125 °C			Unit
			Min	Typ ^[1]	Max	Min	Max (85 °C)	Max (125 °C)	
t _{en}	enable time	S to Z or Yn; see Figure 13 ^[2]							
		V _{CC} = 1.4 V to 1.6 V	-	28	43	-	48	52	ns
		V _{CC} = 1.65 V to 1.95 V	-	23	35	-	38	42	ns
		V _{CC} = 2.3 V to 2.7 V	-	17	27	-	29	32	ns
		V _{CC} = 2.7 V to 3.6 V	-	14	25	-	27	30	ns
t _{dis}	disable time	S to Z or Yn; see Figure 13 ^[3]							
		V _{CC} = 1.4 V to 1.6 V	-	9	20	-	25	30	ns
		V _{CC} = 1.65 V to 1.95 V	-	6	15	-	20	23	ns
		V _{CC} = 2.3 V to 2.7 V	-	5	11	-	14	16	ns
		V _{CC} = 2.7 V to 3.6 V	-	4	10	-	12	14	ns
t _{b-m}	break-before-make time	see Figure 14 ^[4]							
		V _{CC} = 1.4 V to 1.6 V	-	19	-	4	-	-	ns
		V _{CC} = 1.65 V to 1.95 V	-	17	-	4	-	-	ns
		V _{CC} = 2.3 V to 2.7 V	-	13	-	2	-	-	ns
		V _{CC} = 2.7 V to 3.6 V	-	10	-	2	-	-	ns

[1] Typical values are measured at T_{amb} = 25 °C and V_{CC} = 1.5 V, 1.8 V, 2.5 V and 3.3 V respectively.

[2] t_{en} is the same as t_{PZH} and t_{PZL}

[3] t_{dis} is the same as t_{PLZ} and t_{PHZ}

[4] Break-before-make guaranteed by design.

12.1 Waveform and test circuits

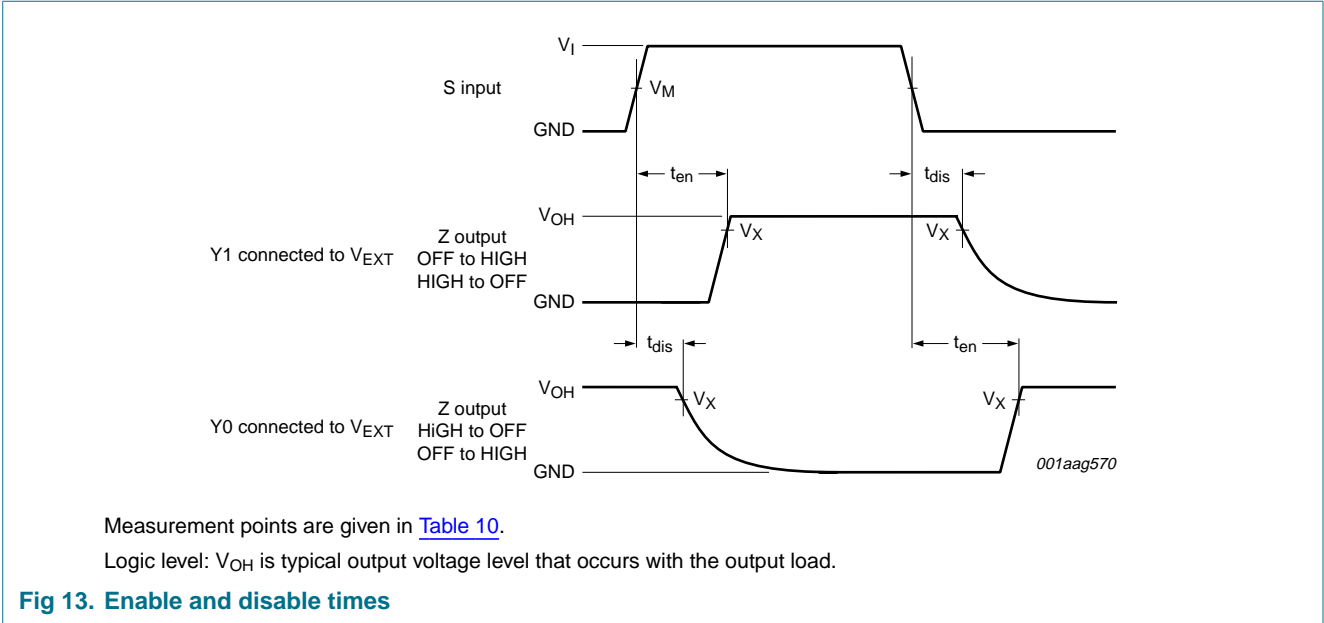
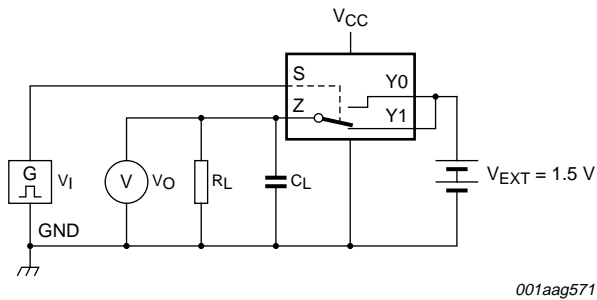


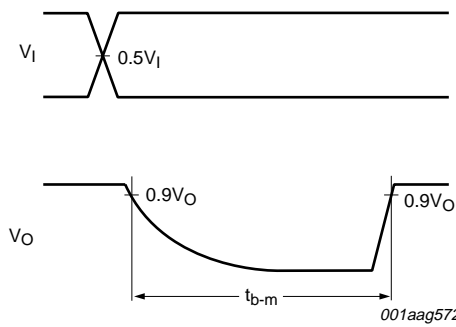
Table 10. Measurement points

Supply voltage	Input	Output
V_{CC}	V_M	V_X
1.4 V to 3.6 V	$0.5V_{CC}$	$0.9V_{OH}$



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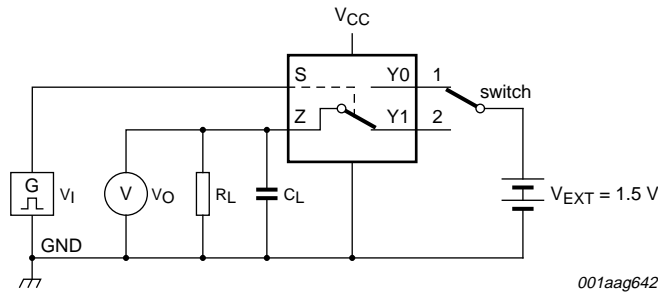
a. Test circuit



001aag572

b. Input and output pulse definitions

Fig 14. Test circuit for measuring break-before-make timing



001aag642

Test data is given in [Table 11](#).

Definitions test circuit:

R_L = Load resistance.

C_L = Load capacitance including jig and probe capacitance.

V_{EXT} = External voltage for measuring switching times.

Fig 15. Load circuit for switching times

Table 11. Test data

Supply voltage	Input		Load	
V_{CC}	V_I	t_r, t_f	C_L	R_L
1.4 V to 3.6 V	V_{CC}	≤ 2.5 ns	35 pF	50 Ω

12.2 Additional dynamic characteristics

Table 12. Additional dynamic characteristics

At recommended operating conditions; voltages are referenced to GND (ground = 0 V)

Symbol	Parameter	Conditions	25 °C			-40 °C to +125 °C			Unit
			Min	Typ	Max	Min	Max (85 °C)	Max (125 °C)	
THD	total harmonic distortion	$f_i = 20 \text{ Hz to } 20 \text{ KHz};$ $R_L = 32 \text{ } \Omega;$ see Figure 16 $V_{CC} = 1.4 \text{ V};$ $V_I = 1 \text{ V (p-p)}$	-	0.15	-	-	-	-	%
			-	0.10	-	-	-	-	%
			-	0.015	-	-	-	-	%
			-	0.024	-	-	-	-	%
$f_{(-3\text{dB})}$	-3 dB frequency response	$R_L = 50 \text{ } \Omega;$ see Figure 17 $V_{CC} = 1.4 \text{ V to } 3.6 \text{ V}$	-	60	-	-	-	-	MHz
α_{iso}	isolation (OFF-state)	$R_L = 50 \text{ } \Omega; f_i = 100 \text{ KHz};$ see Figure 18 $V_{CC} = 1.4 \text{ V to } 3.6 \text{ V}$	-	-90	-	-	-	-	dB
Q_{inj}	charge injection	$C_L = 0.1 \text{ nF}; V_{\text{gen}} = 0 \text{ V};$ $R_{\text{gen}} = 0 \text{ } \Omega; f_i = 1 \text{ MHz};$ $R_L = 1 \text{ M}\Omega;$ see Figure 19	-	3	-	-	-	-	pC
			-	4	-	-	-	-	pC
			-	6	-	-	-	-	pC
			-	9	-	-	-	-	pC

12.3 Test circuits

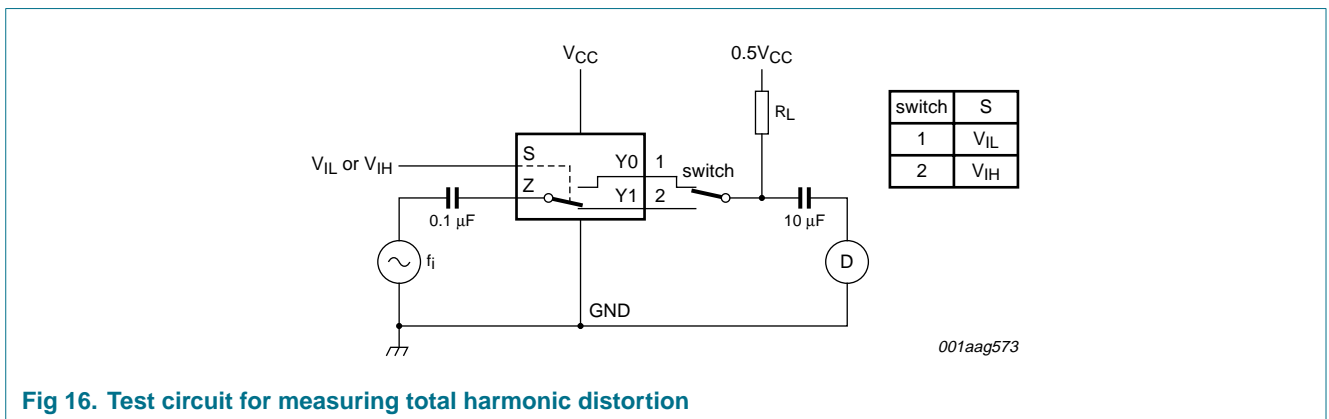
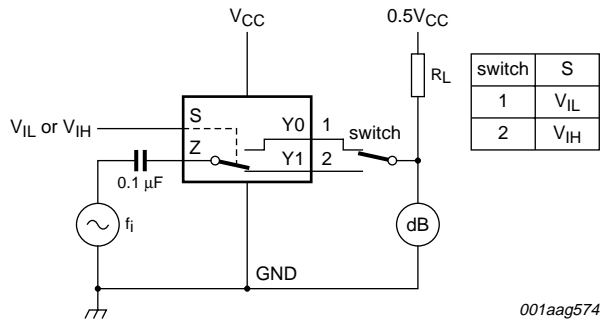


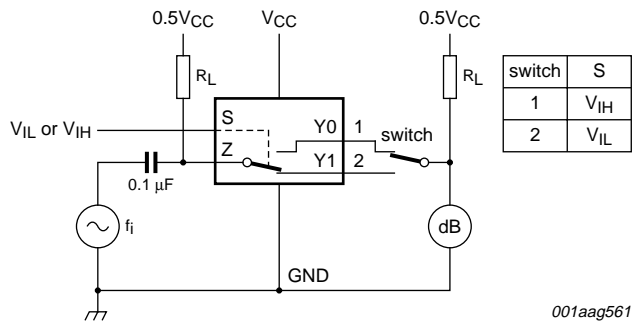
Fig 16. Test circuit for measuring total harmonic distortion



001aag574

Adjust f_i voltage to obtain 0 dBm level at output. Increase f_i frequency until dB meter reads -3 dB.

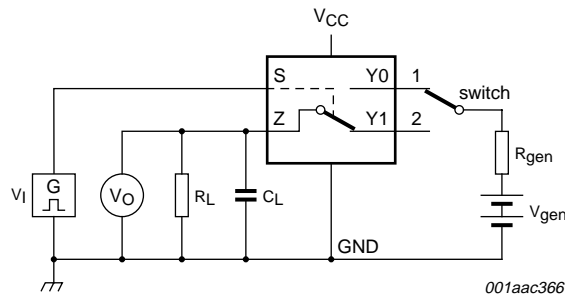
Fig 17. Test circuit for measuring the frequency response when channel is in ON-state



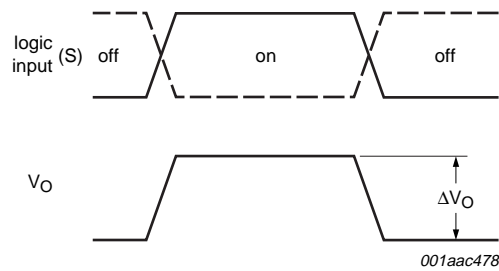
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Adjust f_i voltage to obtain 0 dBm level at input.

Fig 18. Test circuit for measuring isolation (OFF-state)



a. Test circuit



b. Input and output pulse definitions

- Definition: $Q_{inj} = \Delta V_O \times C_L$.
- ΔV_O = output voltage variation.
- R_{gen} = generator resistance.
- V_{gen} = generator voltage.

Fig 19. Test circuit for measuring charge injection

13. Package outline

XSON6: plastic extremely thin small outline package; no leads; 6 terminals; body 1 x 1.45 x 0.5 mm

SOT886

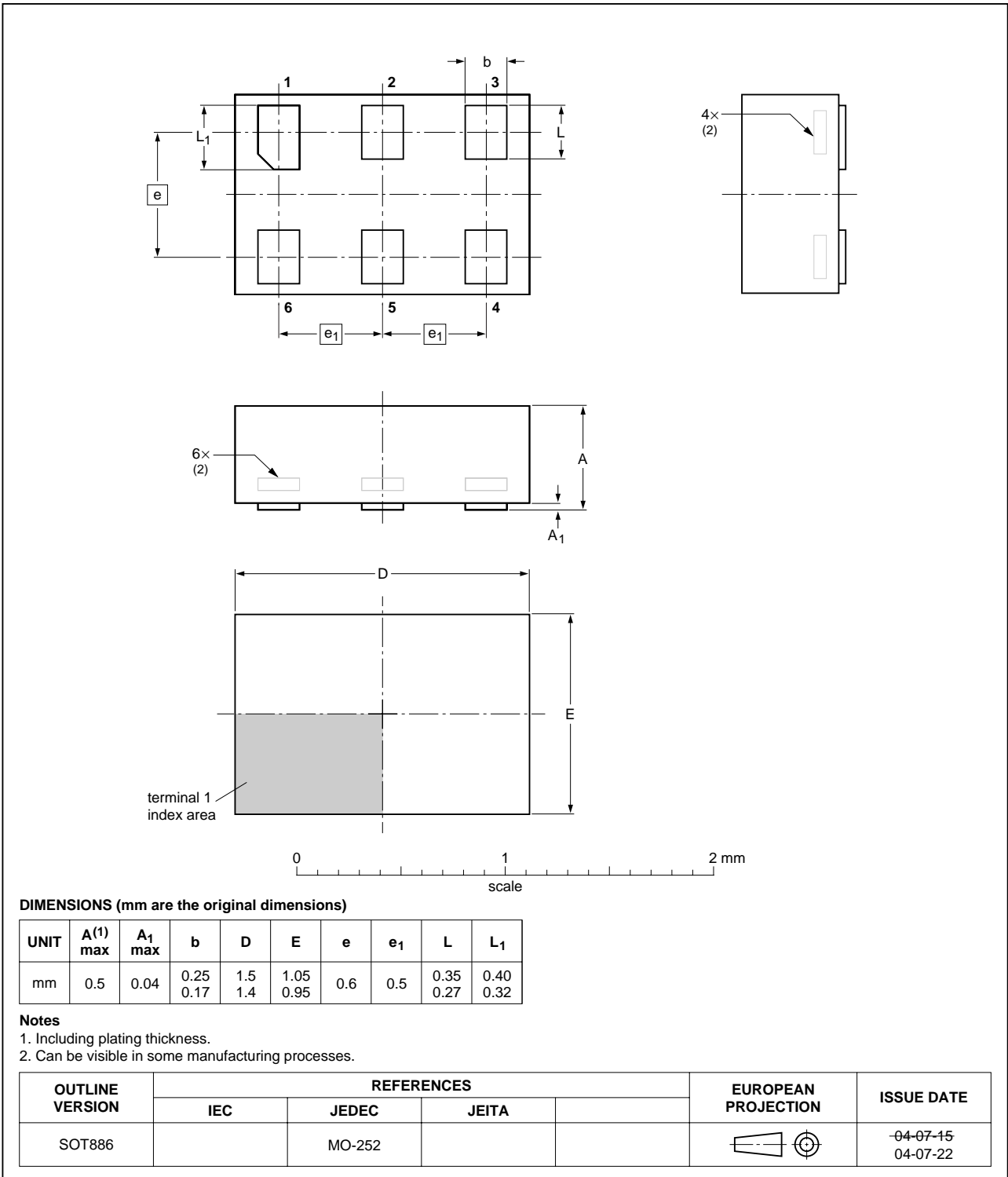


Fig 20. Package outline SOT886 (XSON6)

14. Abbreviations

Table 13. Abbreviations

Acronym	Description
CDM	Charged Device Model
CMOS	Complementary Metal Oxide Semiconductor
DUT	Device Under Test
ESD	ElectroStatic Discharge
HBM	Human Body Model
MM	Machine Model
PDA	Personal Digital Assistant
TTL	Transistor-Transistor Logic

15. Revision history

Table 14. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
NX3L1G3157_1	20071008	Product data sheet	-	-

16. Legal information

16.1 Data sheet status

Document status ^{[1][2]}	Product status ^[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions".

[3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL <http://www.nxp.com>.

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18. Contents

1 General description 1

2 Features 1

3 Applications 1

4 Ordering information 2

5 Marking 2

6 Functional diagram 2

7 Pinning information 2

7.1 Pinning 2

7.2 Pin description 3

8 Functional description 3

9 Limiting values 3

10 Recommended operating conditions 4

11 Static characteristics 4

11.1 Test circuits 5

11.2 ON resistance 6

11.3 ON resistance test circuit and graphs 7

12 Dynamic characteristics 9

12.1 Waveform and test circuits 10

12.2 Additional dynamic characteristics 12

12.3 Test circuits 12

13 Package outline 15

14 Abbreviations 16

15 Revision history 16

16 Legal information 17

16.1 Data sheet status 17

16.2 Definitions 17

16.3 Disclaimers 17

16.4 Trademarks 17

17 Contact information 17

18 Contents 18

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